



Designation: E 2008 – 99

## Standard Test Method for Volatility Rate by Thermogravimetry<sup>1</sup>

This standard is issued under the fixed designation E 2008; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reappraisal. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reappraisal.

### 1. Scope

1.1 This test method covers procedures for assessing the volatility of solids and liquids at given temperatures using thermogravimetry under prescribed experimental conditions. Results of this test method are obtained as volatility rates expressed as mass per unit time. Rates  $\geq 5 \mu\text{g}/\text{min}$  are achievable with this test method.

1.2 Temperatures typical for this test method are within the range from 25°C to 500°C. This temperature range may differ depending upon the instrumentation used.

1.3 This test method is intended to provide a value for the volatility rate of a sample using a thermogravimetric analysis measurement on a single representative specimen. It is the responsibility of the user of this test method to determine the need for and the number of repetitive measurements on fresh specimens necessary to satisfy end use requirements.

1.4 Computer- or electronic-based instruments, techniques, or data treatment equivalent to this test method may also be used.

NOTE 1—Users of this test method are expressly advised that all such instruments or techniques may not be equivalent. It is the responsibility of the user of this test method to determine the necessary equivalency prior to use.

1.5 The values stated in SI units are to be regarded as the standard.

1.6 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this test method to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

### 2. Referenced Documents

#### 2.1 ASTM Standards:

E 473 Terminology Related to Thermal Analysis<sup>2</sup>

E 1142 Terminology Relating to Thermophysical Properties<sup>2</sup>

E 1582 Practice for Calibration of Temperature Scale for Thermogravimetry<sup>2</sup>

<sup>1</sup> This test method is under the jurisdiction of ASTM Committee E-37 on Thermal Measurements and is the direct responsibility of Subcommittee E37.01 on Test Methods and Recommended Practices.

Current edition approved March 10, 1999. Published June 1999.

<sup>2</sup> *Annual Book of ASTM Standards*, Vol 14.02.

### 3. Terminology

#### 3.1 Definitions:

3.1.1 The following terms are applicable to this test method and can be found in Terminologies E 473 and E 1142:

3.1.1.1 *thermogravimetric analysis (TGA)*,

3.1.1.2 *thermogravimetry (TG)*,

3.1.1.3 *volatility*.

#### 3.2 Definitions of Terms Specific to This Standard:

3.2.1 *volatility rate*—the rate of conversion of a solid or liquid substance into the vapor state at a given temperature; mass per unit time.

### 4. Summary of Test Method

4.1 A solid or liquid specimen is confined in an appropriate container with a pinhole opening between 0.33 and 0.38 mm. The confined specimen is heated within a thermogravimetric analyzer either to a temperature and held constant at that temperature for a fixed interval of time (Method A, Fig. 1) or at a slow constant heating rate between temperature limits (Method B, Fig. 2). The mass of the specimen is measured continuously and it or its rate of change is displayed as a function of time or temperature. The volatility rate at any temperature is reported either as the average rate of mass loss per unit time from Method A or as the instantaneous rate of mass loss (first derivative) per unit time from Method B.

### 5. Significance and Use

5.1 Volatility of a material is not an equilibrium thermodynamic property but is a characteristic of a material related to a thermodynamic property which is vapor pressure. It is influenced by such factors as surface area, temperature, particle size, and purge gas flow rate; that is, it is diffusion controlled.

5.2 The extent of containment achieved for specimens in this test method by means of a pinhole opening between 0.33 to 0.38 mm allows for measurement circumstances that are relatively insensitive to experimental variables other than temperature. Decreasing the extent of containment by use of pinholes larger than 0.38 mm will increase the magnitude of the observed rate of mass loss but will also reduce the measurement precision by increasing the sensitivity to variations in other experimental variables.

5.3 Results obtained by this test method are not strictly equivalent to those experienced in processing or handling conditions but may be used to rank materials for their volatility

water at 323 K; 0.33 mm pinhole; 5.285 mg; nitrogen purge at 100 mL/min

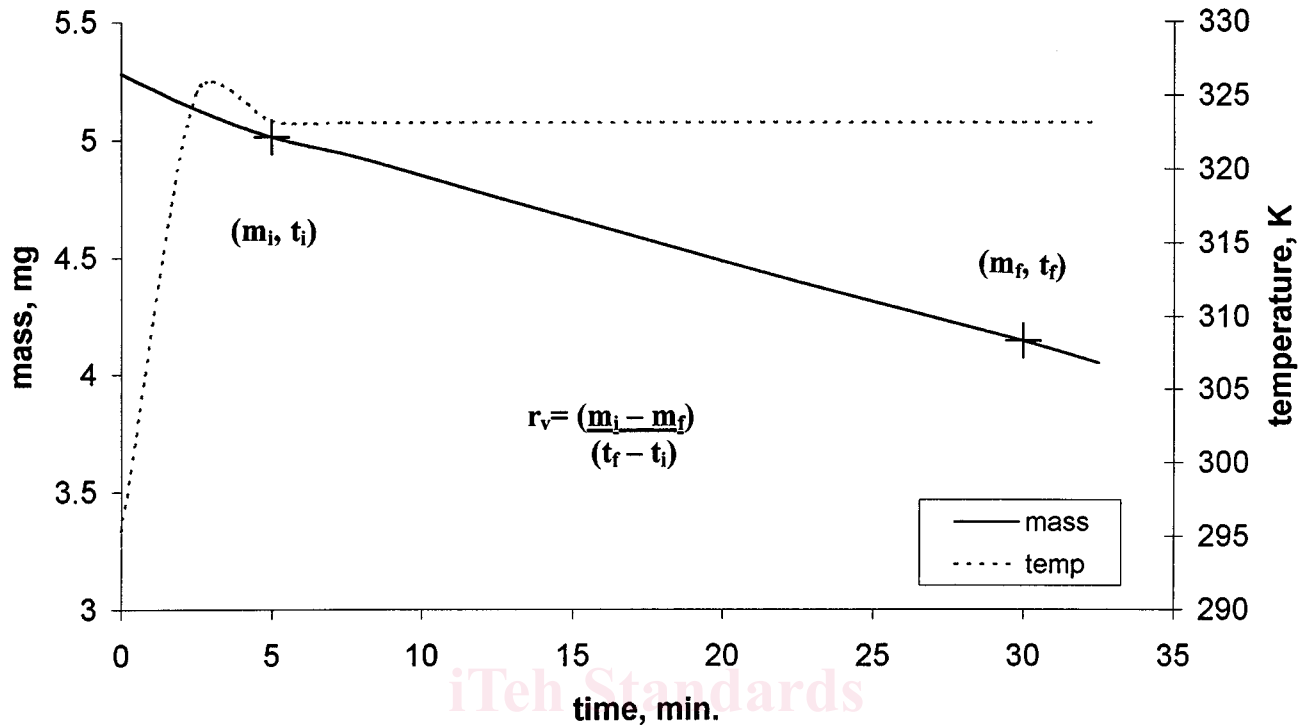


FIG. 1 Method A:  $R_v$  = Average Volatility Rate

in such circumstances. Therefore, the volatility rates determined by this test method should be considered as index values only.

5.4 The volatility rate may be used to estimate such quantifiable values as drying interval or the extent of volatile release from a process.

## 6. Interferences

6.1 Specimens that consist of a mixture of two or more volatile components or that undergo decomposition during this test may exhibit curvature in the mass loss versus time plot of Method A (see Fig. 3). In such cases the volatility rate is not constant and shall not be reported as a singular value.

## 7. Apparatus

7.1 The essential instrumentation required to provide the minimum thermogravimetric analytical capability for this test method includes:

7.1.1 A *thermobalance*, composed of:

7.1.1.1 A *furnace*, to provide uniform controlled heating of a specimen at a constant temperature or at a constant rate within the applicable temperature range of this test method;

7.1.1.2 A *temperature sensor*, to provide an indication of the specimen/furnace temperature to  $\pm 1$  K;

7.1.1.3 A continuously recording *balance*, to measure the specimen mass with a minimum capacity of 100 mg and a sensitivity of  $\pm 10$   $\mu$ g;

7.1.1.4 A means of sustaining the specimen/container under *atmospheric control* of inert gas (nitrogen, helium, and so forth) of 99.9 % purity at a purge rate of 50 to 100 mL/min  $\pm 5$  %.

NOTE 2—Excessive purge rates should be avoided as this may introduce interferences due to turbulence effects and temperature gradients.

7.1.2 A *temperature controller*, capable of executing a specific temperature program by operating the furnace between selected temperature limits at a rate of temperature change of 1 to 2 K/min constant to within  $\pm 0.1$  K/min or to rapidly heat a specimen at a minimum of 50 K/min to an isothermal temperature that is maintained constant to  $\pm 1$  K for a minimum of 30 min.

7.1.3 A *recording device*, either analog or digital, capable of recording and displaying any fraction of the specimen mass signal (TGA curve), including the signal noise versus time or temperature.

7.1.4 *Sealable containers* (pans, crucibles, and so forth), that are inert to the specimen, that will remain gravimetrically stable within the temperature limits of this test method, and that contain a pinhole in the lid of diameter between 0.33 and 0.38 mm.<sup>3</sup>

NOTE 3—The most critical parameters for containers suitable for use with this test method are the pinhole diameter and the lid thickness. Sealable containers of volumes (25 to 50  $\mu$ L) and wall thicknesses (80 to 150  $\mu$ m) commercially available from Mettler-Toledo, Perkin-Elmer Corporation, and TA Instruments, Inc. have been found suitable for this purpose.

<sup>3</sup> The sole source of supply of the 0.33 to 0.38-mm diameter pinhole lids known to the committee at this time is Kalbsey Corporation, 2725 W. CR1500 N., Carbon, IN 47837. If you are aware of alternative suppliers, please provide this information to ASTM Headquarters. Your comments will receive careful consideration at a meeting of the responsible technical committee, which you may attend.